

Notice of References Cited

Application/Control No. 09/935,776	Applicant(s)/Patent Under Reexamination LIEBER ET AL.	
Examiner Shouxiang Hu	Art Unit 2811	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0054709	12-2001	Heath et al.	257/25
	B	US-5,997,832	12-1999	Lieber et al.	423/249
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chung et al., Applied Physics Letters, V76, N15, 2000, p2069-2070
	V	Wolf et al., Silicon Processing for the VLSI Era, Lattice Press, V1, 2000, pages 12-13
	W	Morales et al., Science, V279, 1998, pages 208-211
	X	Tans et al., Nature, V393, 1998, p49-52

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/935,776	Applicant(s)/Patent Under Reexamination LIEBER ET AL.	
	Examiner Shouxiang Hu	Art Unit 2811	Page 2 of 2

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A US-			
	B US-			
	C US-			
	D US-			
	E US-			
	F US-			
	G US-			
	H US-			
	I US-			
	J US-			
	K US-			
	L US-			
	M US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				
	O				
	P				
	Q				
	R				
	S				
	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Haraguchi et al., Applied Physics Letters, V60, 1992, p745-747
V	Yu et al., Applied Physics Letters, V72, 1998, p3458-3460
W	Esfarjani et al., Applied Physics Letters, V74, 1999, p79-81
X	Yamada, Applied Physisc Letters, V76, 2000, p628-630

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.